





TEST REPORT





Product Name:	LED Facial Mask					
Model No.:	SR-M4					
Applicant:	Shenzhen Sunsred Technology Co., Ltd					
Test Procedure:	Entrustment Test					





TEST REPORT

IEC 60601-1-11

Part 1-11: General requirements for basic safety and essential performance -Collateral Standard: Requirements for medical electrical equipment and medical electrical systems used in the home healthcare environment

Report Number.....: CTNT240429010 Nov. 19, 2024 Date of issue::

Shenzhen Zhongwei Testing Technology Co., Ltd.

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Name of Testing Laboratory preparing the Report::

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Applicant's name: Shenzhen Sunsred Technology Co., Ltd.

Address:: 201, No. 22, Shijing Road, Furnin Community Fucheng Street,

Longhua District, Shenzhen, Guangdong, China

Manufacturer's name.....: Shenzhen Sunsred Technology Co., Ltd.

201, No. 22, Shijing Road, Furnin Community Fucheng Street, Address::

Longhua District, Shenzhen, Guangdong, China

Test specification:

Standard: : IEC 60601-1-11:2015, IEC 60601-1-11:2015/AMD1:2020 for use in

conjunction with IEC 60601-1:2005, IEC 60601-1:2005/AMD1:2012,

IEC 60601-1:2005/AMD2:2020

Test procedure....:: **Entrustment Test**

Non-standard test method....:: N/A

TRF template used: IECEE OD-2020-F1:2021, Ed.1.4

Test Report Form No.....: IEC60601_1_11G

Test Report Form(s) Originator....: UL(US)

Master TRF....:: 2021-09-16

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Remark:

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Test item description		: LE	D Facial Ma	ask			
Trade Mark(s)		: N/	Α				
Model/Type reference		: SF	R-M4				
Ratings:			Charging input: 5V ===1A				
		Ba	attery: 18650	3.7V == 3000	OmAh, 11.1W	/ h	
(120110110110110110110110110110110110188808)							
General remarks:							
"(See Enclosure #)" refers "(See appended table)" refe			(//////////////////////////////////////		eport.		N.
Throughout this report a		comma / 🖂 p	oint is use	d as the deci	mal separat	or.	
Other impressions was a							
Other important notes: 1. If you have any objection company within 15 days fro					e submit a w	ritten report	to the
2. Entrusting test only responsible to understand the qua				es, and the tes	st results are	used by the	entrusting
3. This test report is invalid	with	out the "test s	tamp".				
4. This report may not be re	epro	duced in part	without per	mission to avo	oid ambiguou	s interpreta	ıtion.
5. Test items with "*" are ur	naut	horized items					
6. The remaining samples of the samples are not collected.							pection report.
Testing procedure and test	ting	location					
Laboratory		Shenzhen Zh	nongwei Tes	ting Technolog	gy Co., Ltd.		
name							
Testing location/address:	<u>.</u>			Lijia Road, H , Shenzhen, C			enggang
Testing procedure		TL 🛛 RM	T 🗌 SM7	□ WMT □	TMP 🗌		
2.0							30
Tested By		Jackie Chen			(1		
(Test Engineer)		Jackie Chen		Jackie	. Uhen.		
D : 15	<u>.</u>						
Reviewed By		Airan Lu		Airan	n Lu		
(Supervisor)				Hirw	Lu		
					ING TEC		
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Approved By		ECALA I		A11/2/0	ALT E	5)	
(Chief Engineer)		Flight Lee		KEN	KINI JS	₽ .	
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